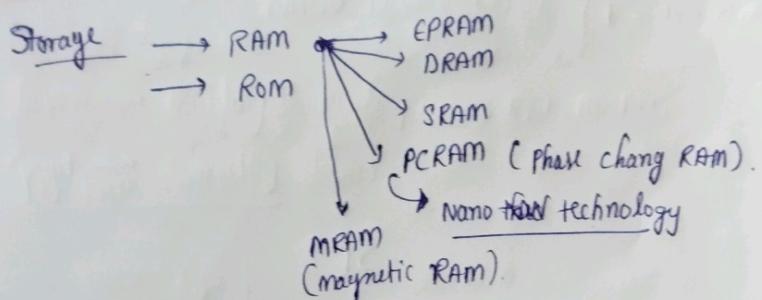
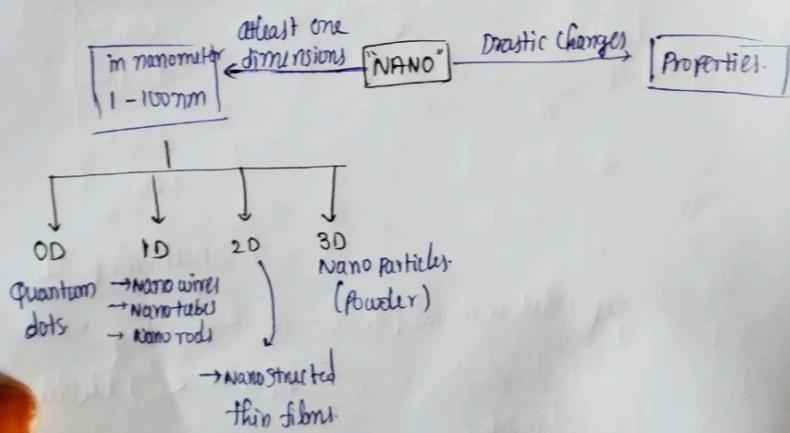


Nishad D. Pandey NANO DEVICE ENGINEERING



Data Storage vs. Information storage devices?



Drastic change in the properties:

1. Increased Surface to volume ratio.
 2. High concentration of atom/molecules at the surface
 3. Dominant Surface forces.
 4. Plasmonic resonance effects.
 5. Confined energy states [quantum Confinement].
 6. Dramatic physical chemical biological changes.

```

graph TD
    A[Nanocomposite] --> B[Size, Shape, Composition]
    A --> C[lowered phase transition temp]
    A --> D[increased mech strengths]
    A --> E[different optical effects]
    A --> F[Altered electrical Conductivity.]
  
```

No. of atoms

$$1 - \underbrace{10}_{\text{molecule}} = \underbrace{10^2}_{\text{nano particles}} - \underbrace{10^3}_{\text{}} - \underbrace{10^4}_{\text{}} - \underbrace{10^5}_{\text{}} - \underbrace{10^6}_{\text{BULK}}$$

Q: A spherical particle \rightarrow 100 nm diameter then
 i) Volume ($\frac{4}{3}\pi r^3$) ii) surface area ($4\pi r^2$)

$$V = \frac{4}{3}\pi (50 \times 10^{-9})^3$$

$$V = 5.22 \times 10^{-22} \text{ m}^3$$

$$\frac{S}{V} = \frac{3.14 \times 10^{-14} \text{ m}^2 / \text{m}^3}{5.22 \times 10^{-22}} \Rightarrow \frac{S}{V} = \frac{6 \times 10^7 \text{ m}^{-1}}{\text{SURFACE EFFECTIVE}}$$

If diameter \rightarrow 100 m.

$$V = 5.22 \times 10^{-22} \times \frac{1}{10^{-27}}$$

$$V = 5.22 \times 10^5 \text{ m}^3$$

$$\frac{S}{V} = 3.14 \times 10^{-14} \times \frac{10^{-18}}{10^{-27}}$$

$$\frac{S}{V} = 3.14 \times 10^4 \text{ m}^2$$

$$\frac{S}{V} = 0.06 \text{ units/}$$

$$E_1 = \frac{hc}{\lambda} \Rightarrow \frac{hc}{100 \times 10^{-9}} = \frac{hc}{10^{-8}}$$

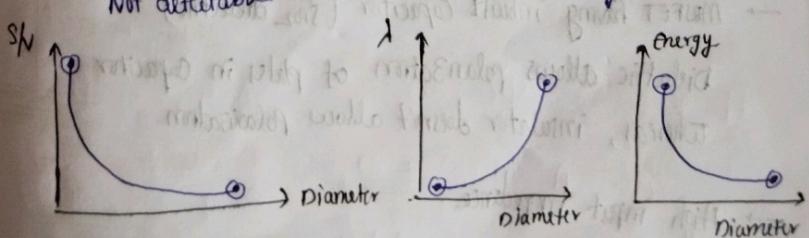
$$= hc \times 10^7$$

Not detectable

$$E_2 = \frac{hc}{\lambda} = \frac{hc}{100} = \frac{hc}{10^{-18}}$$

$$= hc \times 10^{-2}$$

Radio regm.



Changed
Magnetic Properties.
(Ferro, Dia, Anti, Ferri,
Paramagnetic (Superpara))?

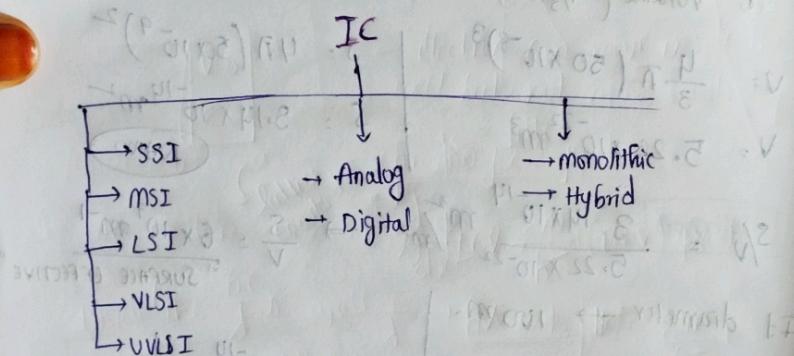
Effective
Surface
Chemical reactions.

manish sri

NAND DEVICE ENGG (1 - 100 nm)

Device → Building blocks (Capacitor, BJT, MOSFET, - - -)

Circuit → Computing devices



IC fabrication:

Silicon wafer → on which fabrication takes place.

→ MOSFET >> BJT

→ mosfet takes less place

→ MOSFET has less power consumption than BJT

→ MOSFET is Voltage controlled device

→ MOSFET having inbuilt Capacitor (SiO_2 dielectric)

Dielectric allows polarization of plates in capacitor whereas, insulator doesn't allow polarization.

→ High input impedance

→ Easy fabrication.

drawback: "Low speed."

MOSFET OPERATION:

Energy levels and quantum confinement effects

NISTED SIR:-

$$3D \rightarrow 0D$$

$$D_f + D_c = 3$$

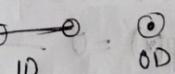
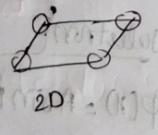
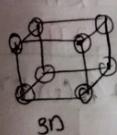
Degree of freedom

Degree of Confinement

	D_f	D_c
3D	3	0
2D	2	1
1D	1	2
0D	0	3

Q: If 0D nano material is having 0D then where is the particle going or moving? (Homework)!

In case of Confinement we are decreasing the no. of atoms on the Surface.

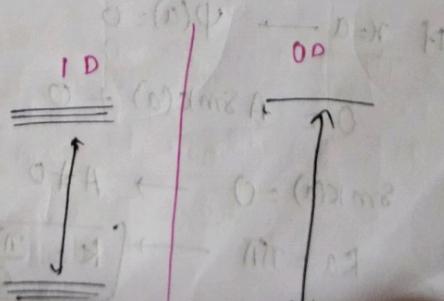
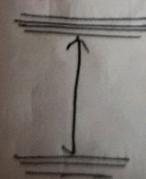


Energy spectrum of 3D: It is having more no. of electrons and more no. of energy levels

CB
VB
Energy levels and less Band gap.

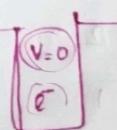
Band gap.

Energy spectrum of 2D:



As the no. of atoms decreases the no. of energy levels decreases and bandgap increases. As the bandgap increases the properties of the material changes

1D nano material:



electron can move inside the well but cannot move outside

(lattice constant)

Schrodinger equation:

$$\frac{d^2\psi}{dx^2} + \frac{2m}{\hbar^2} (E - V) \psi(x) = 0$$

Inside the 1-D well: $\rightarrow [V=0]$

$$\frac{d^2\psi}{dx^2} + \frac{2m}{\hbar^2} (E) \psi(x) = 0$$

$\rightarrow k^2$

$$k^2 = \frac{2m}{\hbar^2} E$$

$$k = \frac{\sqrt{2mE}}{\hbar}$$

$$E = \frac{(k\hbar)^2}{2m}$$

$$\frac{d^2\psi}{dx^2} + k^2 \psi(x) = 0 \rightarrow \text{solution:}$$

$$\psi(x) = A \sin kx + B \cos kx$$

If $x=0 \rightarrow \psi(x)=0$

$$\psi(0) = A \sin k(0) + B \cos k(0)$$

$$0 = B$$

$$\psi(x) = A \sin kx$$

If $x=a \rightarrow \psi(a)=0$

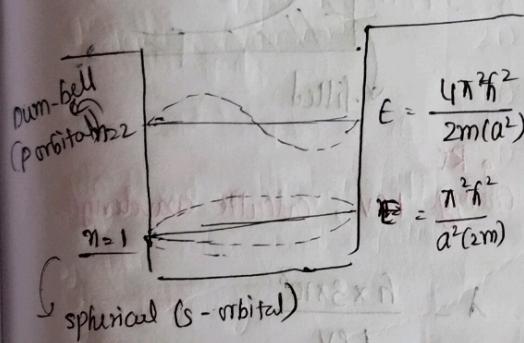
$$0 = A \sin k(a) + 0$$

$$\sin k(a) = 0 \rightarrow A \neq 0$$

$$ka = n\pi \rightarrow \boxed{k = \frac{n\pi}{a}}$$

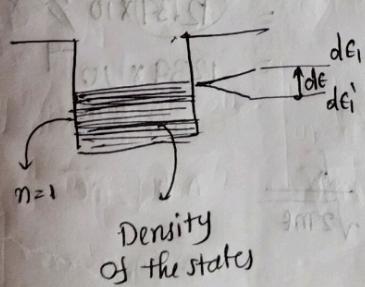
then energy $E = \frac{(n\pi/a)^2 \hbar^2}{2m}$

$$E = \frac{n^2 \pi^2 \hbar^2}{2m}$$



as we are studying for more no. of atoms we will have more no. of states at equidistance of the energy level

$d_n \rightarrow$ no. of allowed energy states given the field/reference



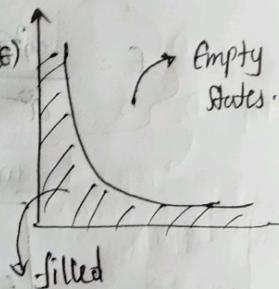
$$g(E) = \frac{dn}{dE}$$

~~$$dE = \frac{2n dn \pi^2 \hbar^2}{2ma^2} \rightarrow \frac{dn}{dE} = \frac{n\pi^2 \hbar^2}{ma^2}$$~~

$$g(E) = \frac{dn}{dE} = \frac{ma^2}{n\pi^2 \hbar^2} \rightarrow \frac{ma^2}{\pi^2 \hbar^2} \frac{\pi \hbar}{a \sqrt{2me}}$$

$$g(\epsilon) = \frac{dn}{d\epsilon} = \frac{a}{\pi^2 h} \sqrt{\frac{m}{2\epsilon}} \quad | \star$$

$$g(\epsilon) \propto \epsilon^{-1/2}$$



Q: An electron with ^{9 KE} Energy 1 eV, calculate wavelength

$$\epsilon = \frac{hc}{\lambda} \Rightarrow \lambda = \frac{h \times 3 \times 10^8}{1 \text{ eV}}$$

$$\lambda = \frac{6.62 \times 10^{-34} \times 3 \times 10^8}{1.602 \times 10^{-19}} \Rightarrow \frac{6.62 \times 3 \times 10^{-7}}{1.602}$$

$$= (12.39 \times 10^{-7}) \times \frac{100}{100} = 1239 \times 10^{-9}$$

Calculate $a = ?$

$$\lambda = \frac{h}{P} = \frac{h}{mv} = \frac{h}{\sqrt{2me}}$$

MANISH :-

1st → oxygen

3rd → Iron

- C
Si → 2nd largest available element
Ge → Temperature stability
Sn → oxidizes easily (SiO_2)
Pb → and SiO_2 is stable also
Environmental Safe
Si in elemental semiconductor is stable
- Si → $150^\circ\text{C} - 200^\circ\text{C}$
Ge → $75^\circ\text{C} - 160^\circ\text{C}$

Direct bandgap & Indirect bandgap semiconductors?

Si → Indirect bandgap (emits heat)

GaAs → high speed (direct bandgap) (emits IR light)

SiC, GaN

LED

MEMS → micro electronic mechanical systems

$$\text{mobility} \rightarrow \text{Si}(\text{Mn}) = 1500 \text{ cm}^2/\text{V-s}$$

$$\text{Ge}(\text{Mn}) = 4000 \text{ cm}^2/\text{V-s}$$

$$\text{GaAs}(\text{Mn}) = 8600 \text{ cm}^2/\text{V-s}$$

$$\mu = \frac{q}{m} \times E$$

drift velocity

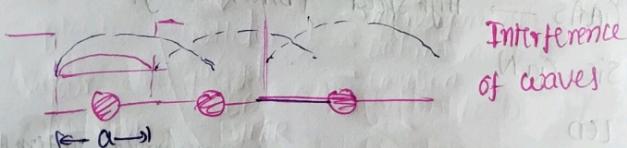


NISHAD :-

Energy levels & quantum confinement effects:-

KE	λ	a
electron 1 eV	1.22 nm	0.613 nm (or) trapped
sev	0.55 nm	0.274 nm

Quantum tunnelling effect As we confined the electron in the potential well but its wave can travel out of the potential well.



$1 \propto a$ → De-Broglie's wave effect
Then it is called as quantum Confinement effect.

Density of states?

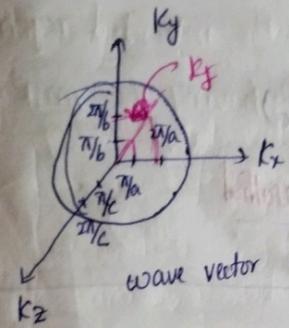
$$g(\epsilon) = \frac{dn}{d\epsilon} = \frac{m a^2}{\pi^2 \hbar^3} \frac{\pi \hbar}{a \sqrt{2m\epsilon}} = \frac{ma}{\pi \hbar \sqrt{2m\epsilon}}$$

$$= \frac{(m)(0.613 \times 10^{-9})}{\pi \hbar \sqrt{(2)(m)(1 \text{ eV})}}$$

Density of states for 3D:

W.K.T.; $k = \frac{n\pi}{a}$; $E = \frac{\hbar^2 k^2}{2m} \Rightarrow k = \frac{\sqrt{2mE}}{\hbar}$

wave vector.



No. of states

$$= \frac{\text{Vol. of sphere}}{\text{Vol. of single cell}}$$

Consider any unit cell.

$$\text{No. of states} = \frac{4/3 \pi (k_f)^3}{(2\pi/a)^3} \quad (a = b = c)$$

$$= \frac{1}{6} \frac{k_f^3 a^3}{\pi^2} \rightarrow \frac{1}{6} \left(\sqrt{\frac{2mE}{\hbar^2}} \right)^3 \frac{a^3}{\pi^2}$$

$$\frac{a^3 (2mE)^{3/2}}{6 \hbar^3 \pi^2}$$

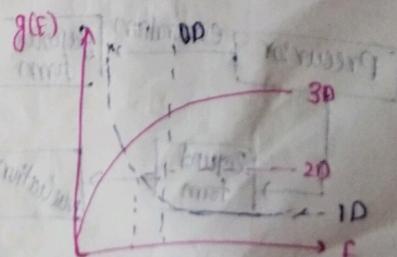
$$\frac{dn}{dE} = \frac{a^3}{28 \hbar^3 \pi^2} \left(\frac{8}{3}\right) E^{1/2} (2m)^{3/2} \rightarrow \text{multiply by 2}$$

$$\frac{dn}{dE} = \frac{1}{2} \frac{a^3}{\hbar^3 (\pi^2)} (2m)^{3/2} E^{1/2}$$

$$g(E) = \frac{dn}{dE} = \frac{a^3 (2m)^{3/2} E^{1/2}}{(2) \hbar^3 (\pi^2)} \rightarrow \text{Density of states}$$

3D Case

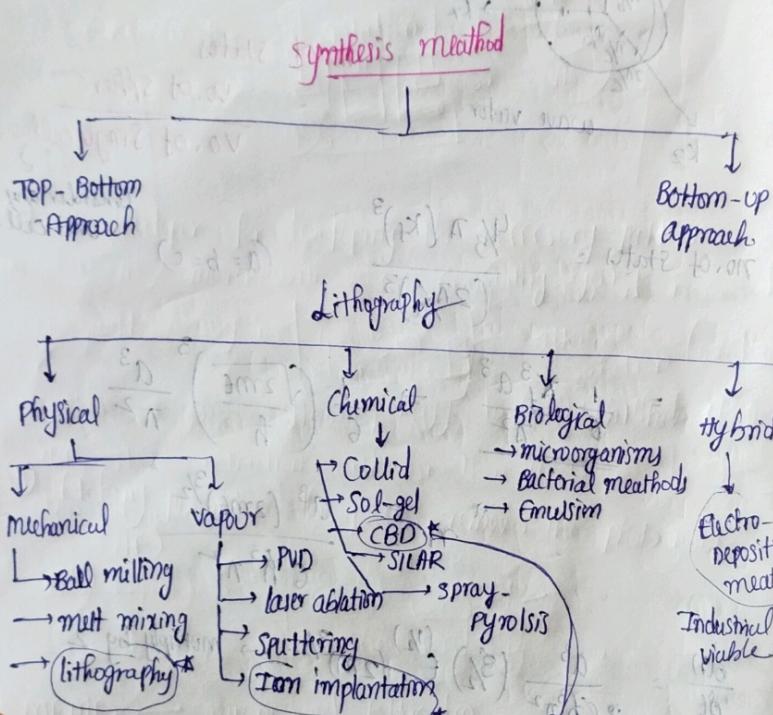
$$g(E) \propto E^{1/2}$$



Home work
Do it for 2D, 0D

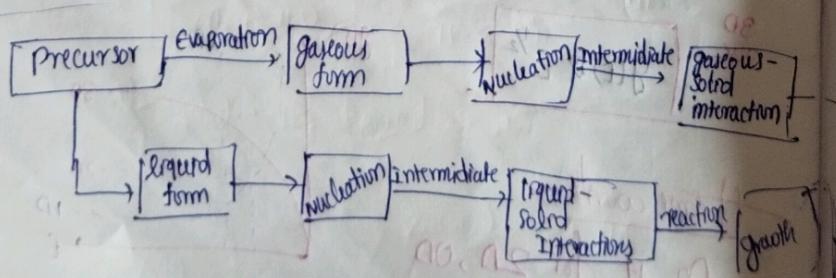
$$\text{for } 20 \rightarrow g(\epsilon) \propto \epsilon^0$$

$$\text{for } 00 \rightarrow g(\epsilon) \propto 2\delta(\epsilon - \epsilon_c)$$

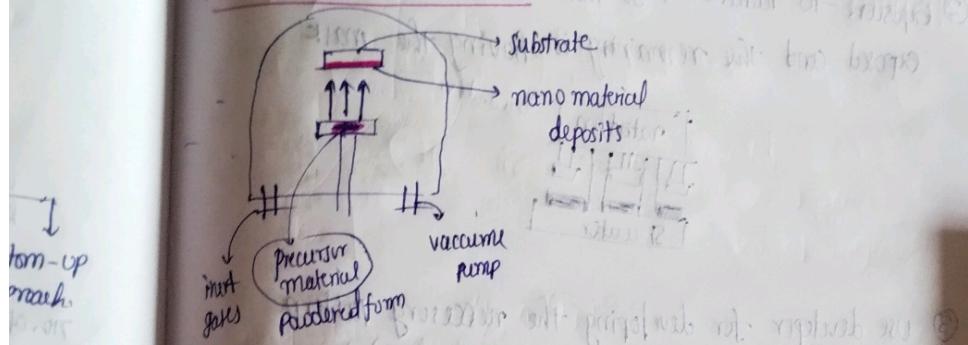


Principles for synthesis method:

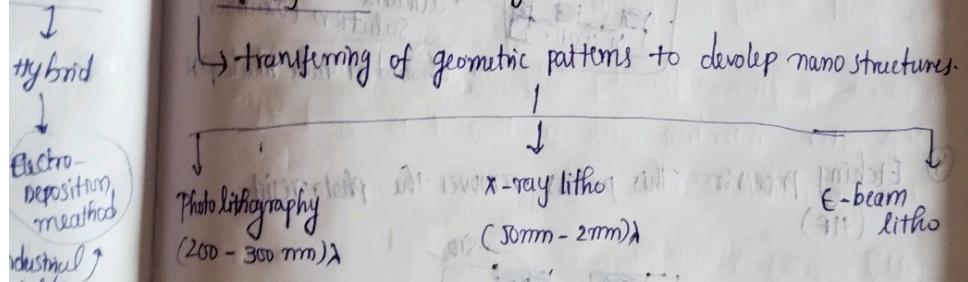
- Precursor, evaporation/liquid/gas.
- Nucleation.
- Growth



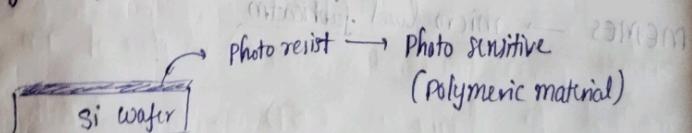
Thermal evaporation method



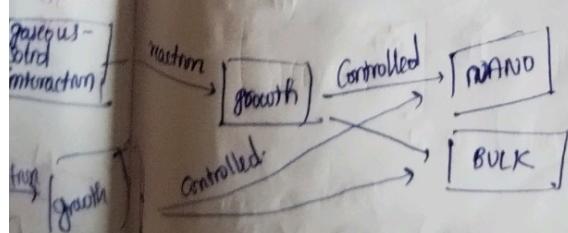
Lithography process : Devicing nano structures —



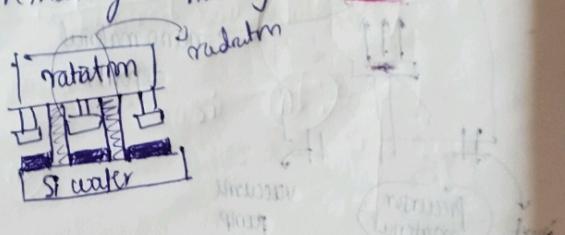
① Coating the photoresist on Si wafer.



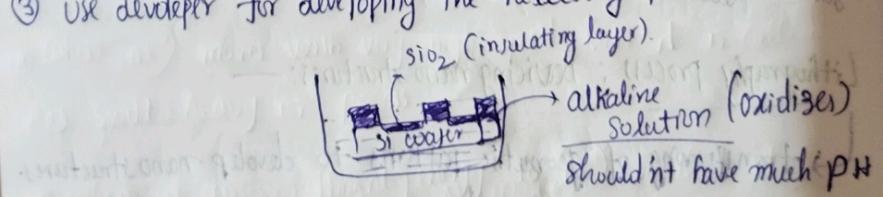
PTO \rightarrow



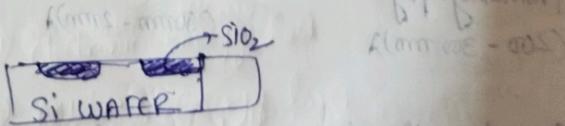
- ② Exposure to radiations: So that the irradiated region gets exposed and the remaining is having the mask.



- ③ Use developer for developing the necessary pattern.



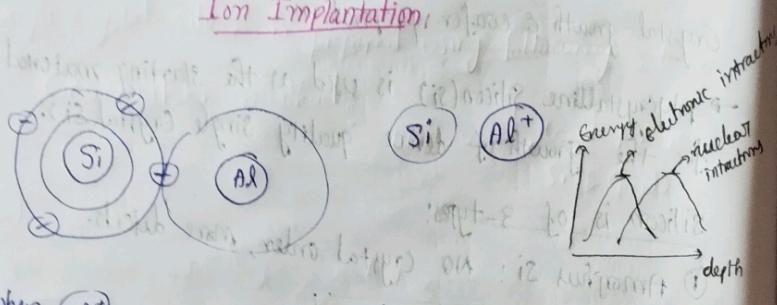
- ④ Etching process: This process removes the photo resist (HF)



MEMS → micro level fabrication

NISHAD:

Ion Implantation



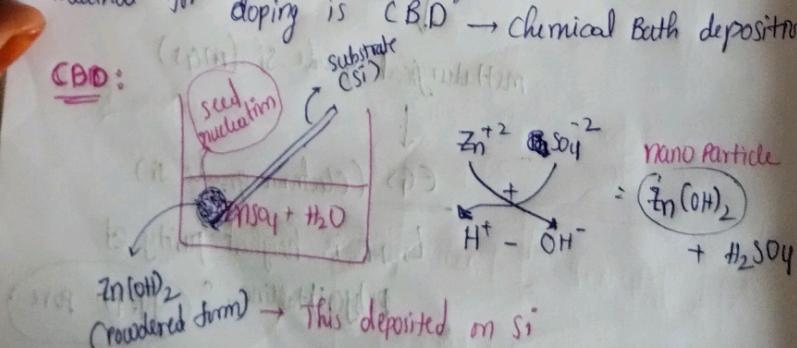
④ When Al^+ moves with very high speed then it is called as Swift heavy ion process.

⑤ When we give sufficient energy to Al^+ so that it just stops after interaction with Si then it is called as Ion implantation method.

- Al^+ experiences
- ① Electronic energy loss
 - ② Nuclear energy loss

Simple process (But not so accurate) in place of ion implantation method for doping is "C.B.D" \rightarrow Chemical Bath deposition.

CBD:



When we heat the "sol" then Zn(OH)_2 ~~gets~~ oxidation gives "ZnO"

- we can control the quantity of nano particle by how much chemical we are using.
- when we keep the si for more time then it completely remove ZnO due to Aetic H₂SO₄.
- we can also dope another nano particles by changing the chemical and also in what ratio we are using them for deposition.

1:2 ratio of $1 \rightarrow \text{ZnSO}_4$ & $2 \rightarrow \text{Al}_2\text{SO}_4$ we get
 ZnAl(OH)_2 nano particle for deposition.

1780m + 1781 : 2000018

2000018 2000018 2000018 price refund

1780m + 1781 : 2000018

1780m + 1781 : 2000018

1780m

1780m

4

NISHAD :-

SRIM/TRIM \rightarrow Software for stopping potential (ion implantation method).

Ostwald's ripening ?

- Concentration precursor sol
 - Volume of sol
 - temperature
 - pH
 - time
- } these control the "CBP"

SILAR (successive ionic layer adsorption and reaction).

We have to dip the rod successively into the beakers.

